

STP410N4F7AG

Automotive-grade N-channel 40 V, 1.5 mΩ typ., 180 A STripFET™ F7 Power MOSFET in a TO-220 package

Datasheet - production data

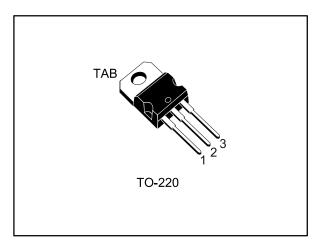
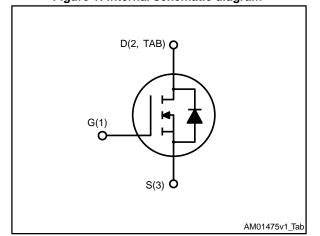


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	Ι _D	Ртот
STP410N4F7AG	40 V	1.8 mΩ	180 A	365 W

- Designed for automotive applications and AEC-Q101 qualified
- Among the lowest R_{DS(on)} on the market
- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low onstate resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

Order code	Marking	Package	Packing
STP410N4F7AG	410N4F7	TO-220	Tube

Contents STP410N4F7AG

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STP410N4F7AG Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V _{DS}	Drain-source voltage	40	V	
V_{GS}	Gate-source voltage	±20	٧	
Ip ⁽¹⁾	Drain current (continuous) at T _{case} = 25 °C	180	۸	
ID ¹⁷	Drain current (continuous) at T _{case} = 100 °C	180	Α	
I _{DM} ⁽²⁾	Drain current (pulsed)	720	Α	
Ртот	Total dissipation at T _{case} = 25 °C	365	W	
E _{AS} (3)	Single pulse avalanche energy	1.9	J	
T _{stg}	Storage temperature range	55 to 175	°C	
Tj	Operating junction temperature range			

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit	
R _{thj-case}	Thermal resistance junction-case	0.41	9 C AA4	
R _{thj-amb}	Thermal resistance junction-ambient max	62.5	°C/W	

 $^{^{(1)}}$ Current is limited by package, the current capability of the silicon is 350 A at 25 $^{\circ}\text{C}.$

⁽²⁾ Pulse width is limited by safe operating area.

 $^{^{(3)}}T_j \le 175~^{\circ}C, I_{av}=80A$

Electrical characteristics STP410N4F7AG

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 4: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	40			V
	Zoro goto voltago drain	$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V}$			10	
IDSS	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 40 \text{ V},$ $T_{case} = 125 \text{ °C}^{(1)}$			100	μΑ
Igss	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = 20 V			200	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2.5		4.5	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 90 A		1.5	1.8	mΩ

Notes:

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	11700	ı	
Coss	Output capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0 V	-	3500	ı	pF
C _{rss}	Reverse transfer capacitance	VBS = 20 V, 1 = 1 Winz, VBS = 0 V	-	390	ı	Pi
Q_g	Total gate charge	$V_{DD} = 20 \text{ V}, I_D = 180 \text{ A}, V_{GS} = 10 \text{ V}$	-	140	ı	
Qgs	Gate-source charge	(see Figure 14: "Test circuit for	-	65		nC
Q_{gd}	Gate-drain charge	gate charge behavior")	-	27	-	

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 20 \text{ V}, I_D = 90 \text{ A R}_G = 4.7 \Omega,$	-	35	-	
tr	Rise time	V _{GS} = 10 V (see Figure 13: "Test circuit for resistive load switching	-	200	-	
t _{d(off)}	Turn-off delay time		-	110	-	ns
tf	Fall time	times" and)	-	44	-	

⁽¹⁾Defined by design, not subject to production test.

Table 7: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} ⁽¹⁾	Source-drain current		-		180	Α
V _{SD} ⁽²⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 90 A	-		1.3	V
t _{rr}	Reverse recovery time	I _{SD} = 180 A, di/dt = 100 A/μs,	1	74.4		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 32 V, T _j = 25 °C (see <i>Figure 15</i> : "Test circuit for inductive load	1	115		nC
I _{RRM}	Reverse recovery current	switching and diode recovery times")	-	3.1		Α

Notes:

 $^{^{(1)}}$ Current is limited by package, the current capability of the silicon is 350 A at 25 $^{\circ}$ C.

 $^{^{(2)}}$ Pulse test: pulse duration = 300 $\mu s,$ duty cycle 1.5%.

2.1 Electrical characteristics (curves)

Figure 2: Safe operating area GADG260520161425SOA Ι_D (A) 10² t_p= 100µs Operation in this area is limited by R_{DS(on)} 10¹ t_p= 1ms T _j≤ 175 °C T_c= 25 °C t_p= 10ms single pulse 10° $\bar{V}_{DS}(V)$ 10° 10¹

Figure 3: Thermal impedance K GADG260520161440ZTH δ =0.5 0.2 0.01 0.05 0.02 0.01 Single pulse $Z_{n=k^*R_{npc}}^{-k^*R_{npc}}$ δ =b/T δ =b/T δ =10 $^{-1}$ δ 10 $^{-2}$ 10 $^{-1}$ δ (s)

Figure 4: Output characteristics

GADG260520161449OCH

(A)

V_{GS} = 7, 8, 9, 10 V

250

V_{GS} = 6 V

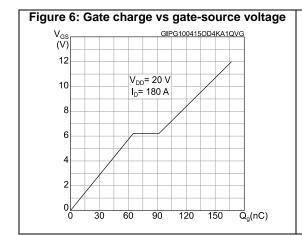
200

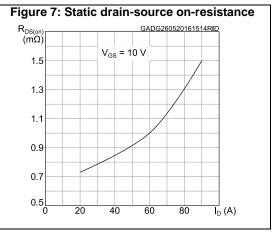
V_{GS} = 5.5 V

150

0

1 2 3 4 5 V_{DS} (V)





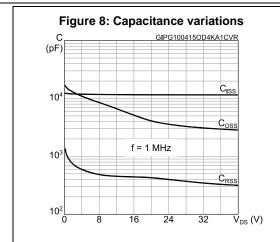


Figure 9: Normalized gate threshold voltage vs temperature

V_{GS(th)}
(norm.)

1.2

1.0

I_D = 250 µA

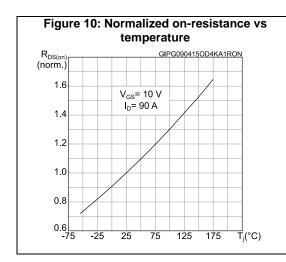
0.8

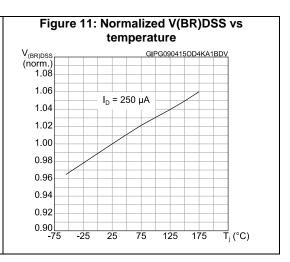
0.6

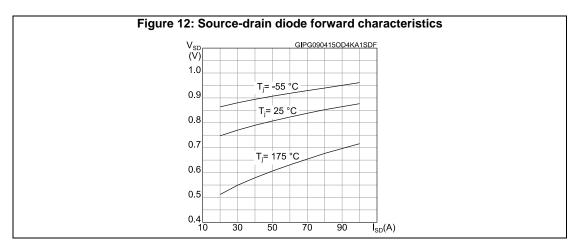
0.4

0.2

-75 -25 25 75 125 175 T_j (°C)







Test circuits STP410N4F7AG

3 Test circuits

Figure 13: Test circuit for resistive load switching times

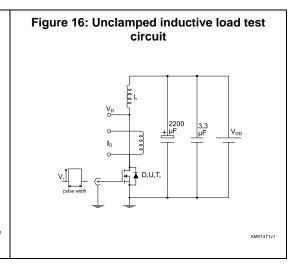
Figure 14: Test circuit for gate charge behavior

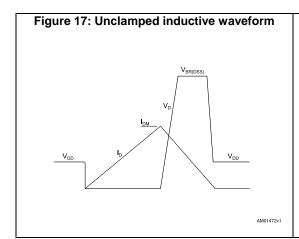
12 V 47 kΩ 100 nF D.U.T.

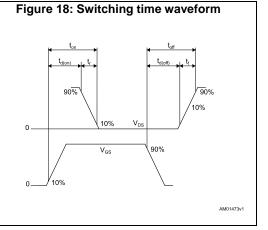
Vos 1 1 kΩ 100 nF D.U.T.

AM01469v1

Figure 15: Test circuit for inductive load switching and diode recovery times







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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



4.1 TO-220 package information

Figure 19: TO-220 type A package outline

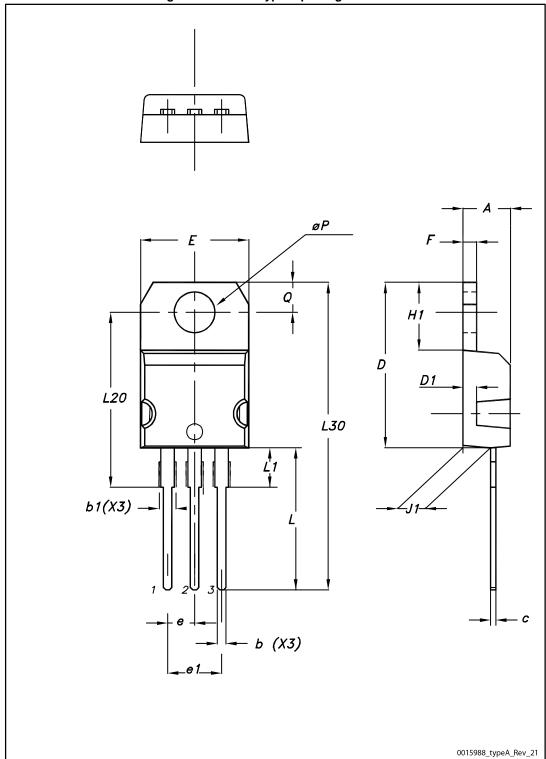


Table 8: TO-220 type A mechanical data

Dim	mm		
Dim.	Min.	Тур.	Max.
А	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
С	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øΡ	3.75		3.85
Q	2.65		2.95

Revision history STP410N4F7AG

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
25-May-2016	1	First release.

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